



Photon Efficiency Measurement Using Z Tag & Probe

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Introduction

- We have measured the efficiencies of different photon selections using the Z Tag and Probe method:
 - e.g. EGM-10-006, QCD-10-019...
- The very same methods will be used with electrons:
 - Electron Identification and Reconstruction efficiencies...
- We have compared and checked the consistency of the results obtained using three different methods:
 - Counting, Fit, Opposite Sign – Same Sign
- The results of this study are documented in the following analysis notes:
 - Electrons: CMS AN-2010/291 (in progress),
 - Photons: CMS AN-2010/292 (v6 is going to be uploaded)

Selection and Samples

- Numbers for different photon selections have been measured:
 - Egamma Loose/Tight, “Exotica”, photon selection for $H \rightarrow \gamma\gamma$...
 - the following results refers to the “Exotica” selection:
 - $\sigma_{\eta\eta} < 0.013 (0.03)$, $H/E < 0.05$
 - $TkIso < 2.0 + 0.001*ET$, $ECALIso < 4.2 + 0.006*ET$
 - $HCALIso < 2.2 + 0.0025*ET$
- Measurements have been carried on using $\sim 35 \text{ pb}^{-1}$ of data using CMSSW_3_8_X.
- The MC samples used are:
 - Zee, Wenu, QCD_enriched, bc_to_e, Photon+Jet.

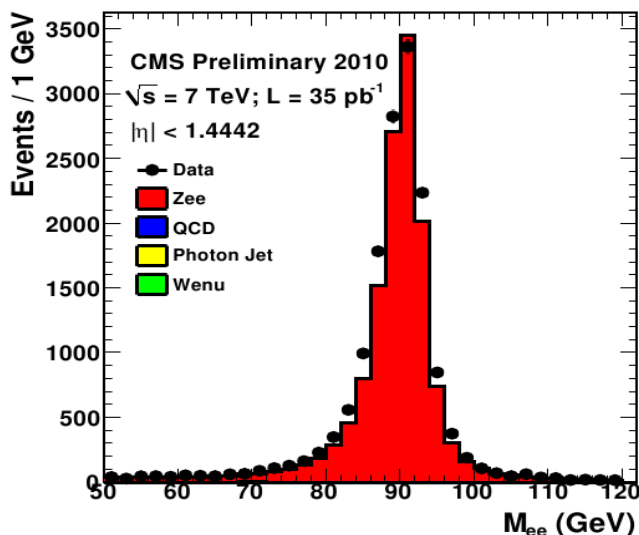
Counting (Overview)

- Tag and Probe definitions:
 - Tag: CiC SuperTight electron with SC ET > 20 GeV
 - Probe: SC ET > 20 GeV
- To reduce the final uncertainty we have used factorization:
 - split the selection into two sets of cuts ($\sigma_{\text{in in}} + \text{H/E} - \text{isolations}$):
 - compute ϵ counting events and performing MC bg subtraction
 - Combine partial efficiencies and correct for possible correlations:
$$(\epsilon_{\text{TOT}}^{\text{MC}} - \epsilon_{\text{fact}}^{\text{MC}})$$
- Statistical errors are binomial.
- Systematics: uncertainty on the background assumed 100% plus 50% of the estimated correlation between the measurements.

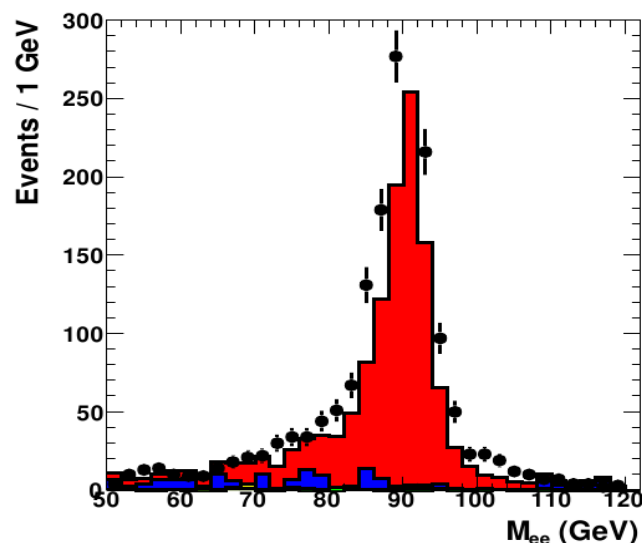
Counting (Isolation)

BARREL

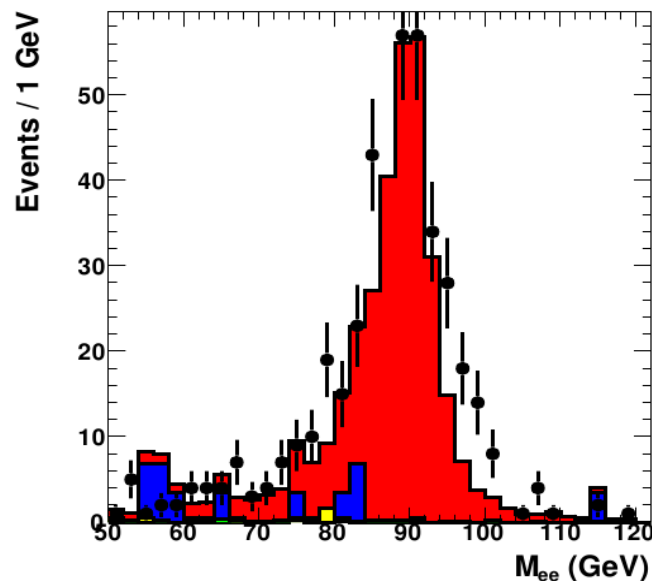
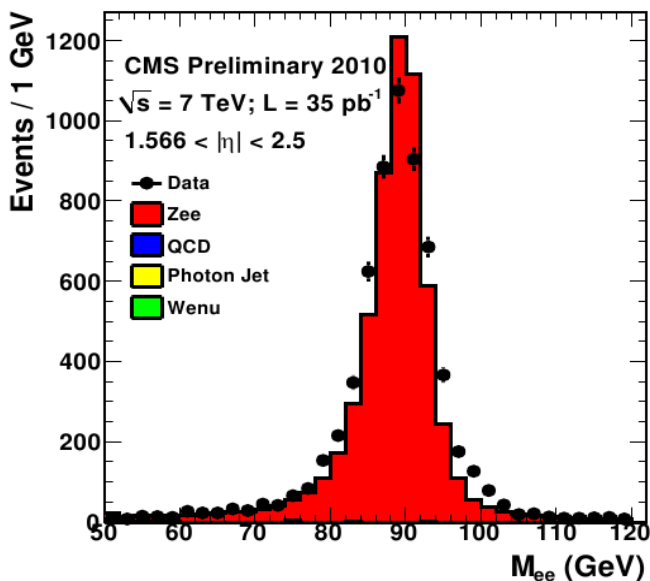
PASSING



FAILING



ENDCAP



Electron energy scaled to match MC.

Counting (Results)

E_T	MC	DATA	R (DATA/MC)
Barrel			
20 - 35	$86.97 \pm 0.16 \%$	$86.49 \pm 0.45 \pm 1.95 \%$	0.995 ± 0.023
35 - 45	$92.21 \pm 0.11 \%$	$90.05 \pm 0.33 \pm 0.16 \%$	0.977 ± 0.004
45 - inf	$93.61 \pm 0.13 \%$	$90.98 \pm 0.43 \pm 0.02 \%$	0.972 ± 0.005
Endcap			
20 - 35	$88.54 \pm 0.22 \%$	$88.28 \pm 0.55 \pm 1.07 \%$	0.997 ± 0.014
35 - 45	$93.20 \pm 0.16 \%$	$92.36 \pm 0.49 \pm 0.35 \%$	0.991 ± 0.007
45 - inf	$94.94 \pm 0.20 \%$	$94.18 \pm 0.62 \pm 0.16 \%$	0.992 ± 0.007

Results available also as a function of η , f_{Brem} and R_9 .

Fit (Overview)

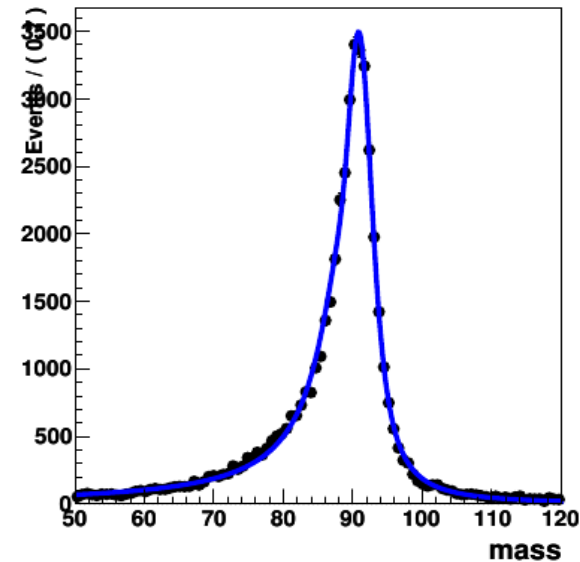
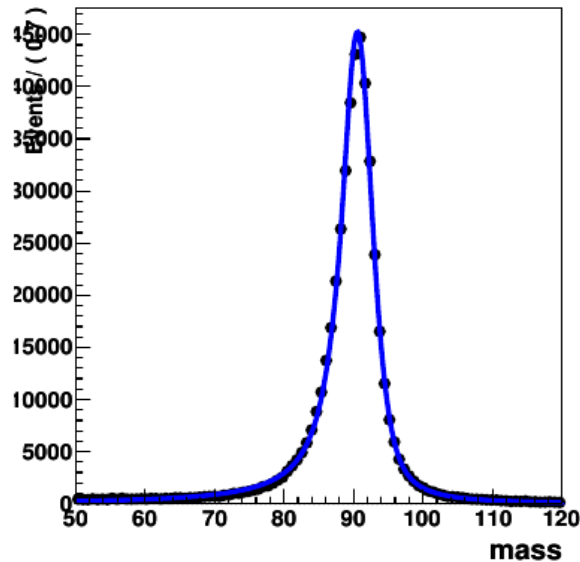
- Take signal shape from MC for passing and failing events:
 - Breit-Wigner (x) Modified Crystall-Ball
(<https://twiki.cern.ch/twiki/bin/view/CMS/ElectronTagAndProbe>)
- Performed extended likelihood fit to data with signal + exponential (background) PDF:
 - tail parameters of signal PDF fixed from MC,
 - get signal and background yields from the fit.
- Systematics:
 - Background: tried different PDF for the background,
 - Energy scale: vary electron energy (by current energy scale uncertainty) and compute corresponding efficiency,
 - Signal: change tail of the PDF and check the contribution.

Fit MC signal only (PDF)

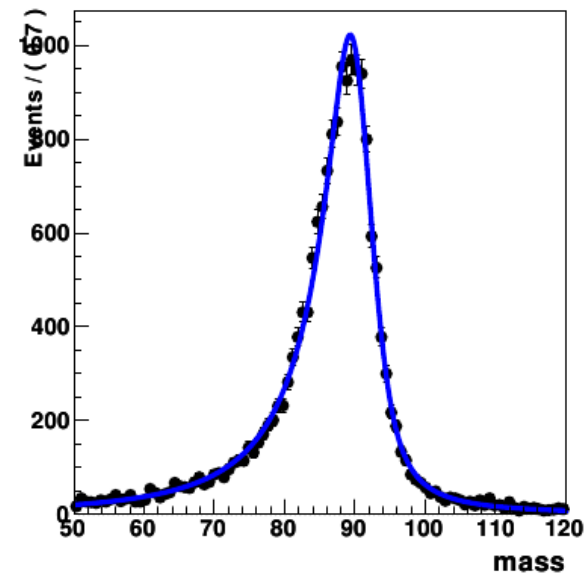
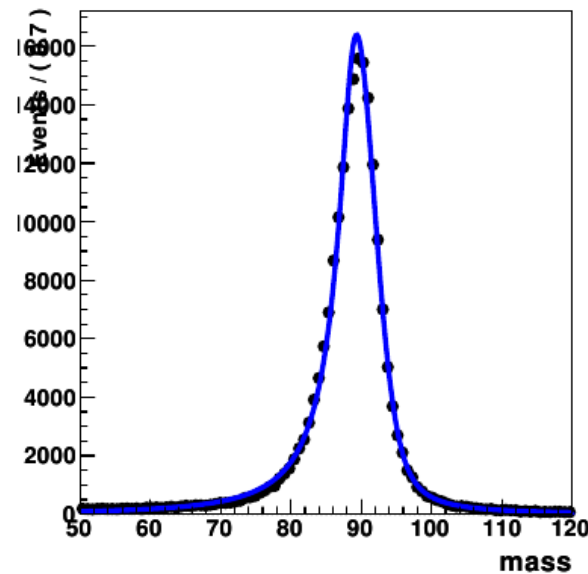
PASSING

FAILING

BARREL



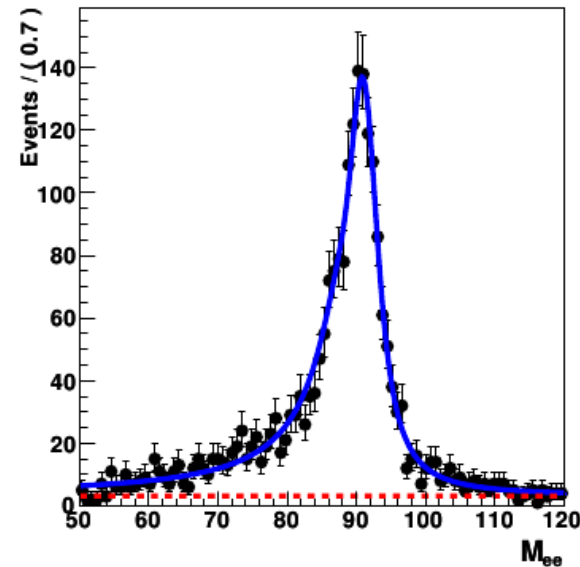
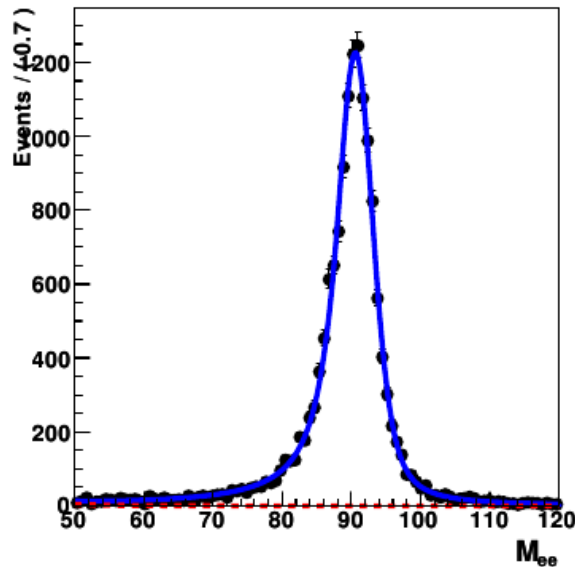
ENDCAP



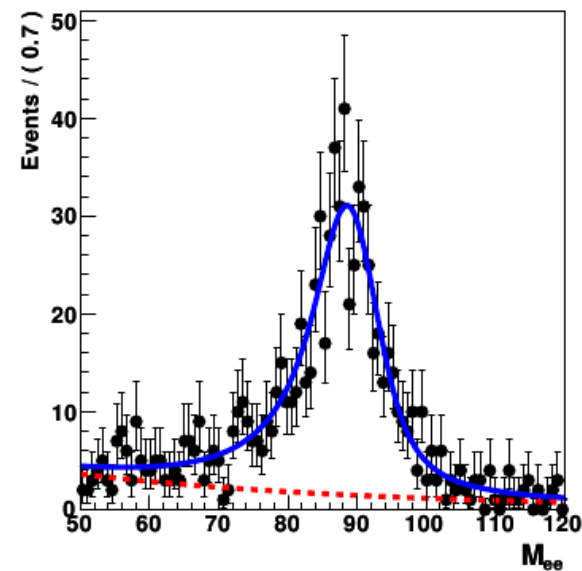
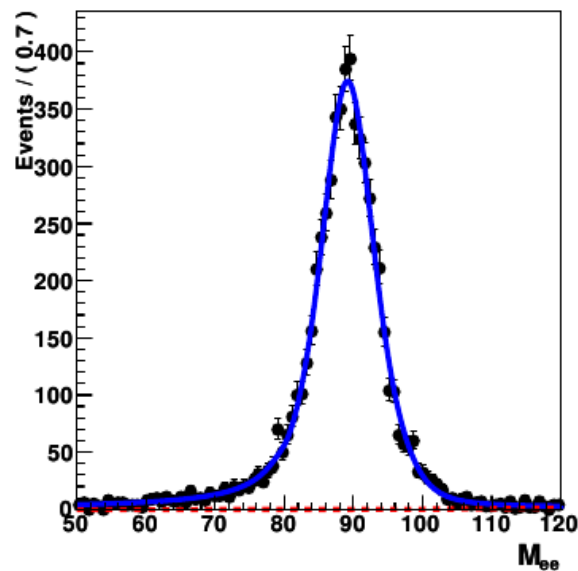
PASSING

FAILING

BARREL



ENDCAP



Fit (Results)

- No factorization is involved here, it has to be checked if factorization could help in reducing uncertainty.

E_T	MC	DATA	R (DATA/MC)
Barrel			
20 - 35	$86.97 \pm 0.16 \%$	$82.23 \pm 1.14 \pm 1.58 \%$	0.945 ± 0.022
35 - 45	$92.21 \pm 0.11 \%$	$89.54 \pm 0.43 \pm 0.55 \%$	0.971 ± 0.008
45 - inf	$93.61 \pm 0.13 \%$	$90.77 \pm 0.52 \pm 0.82 \%$	0.970 ± 0.010
Endcap			
20 - 35	$88.54 \pm 0.22 \%$	$88.89 \pm 1.60 \pm 3.44 \%$	1.004 ± 0.043
35 - 45	$93.20 \pm 0.16 \%$	$90.99 \pm 0.56 \pm 0.43 \%$	0.977 ± 0.008
45 - inf	$94.94 \pm 0.20 \%$	$93.42 \pm 0.10 \pm 0.95 \%$	0.984 ± 0.010

Results available also as a function of eta, fBrem and R9.

OS/SS (Overview)

- Given the number of OS and SS passing and failing events, the signal can be extracted from the following formula:

$$N = \frac{(N_{OS} - N_{SS})}{(1 - 2q)^2} - (B_{OS} - B_{SS})$$

- q = charge mis-id (different for passing and failing events), taken from MC (for failing event can be hardly determined from data)
 - B_{OS} and B_{SS} number of OS/SS background events.
- Systematics:
 - Background events: $100\% * (B_{OS} - B_{SS})$
 - Charge mis-id: assumed 50% error

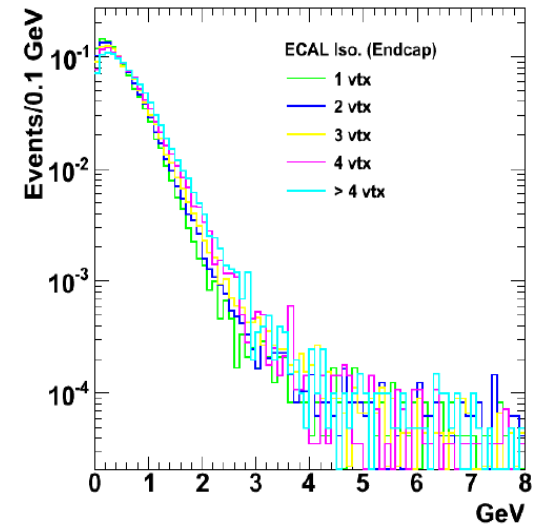
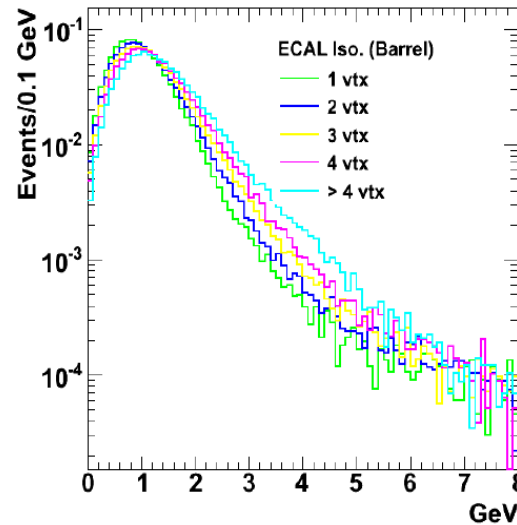
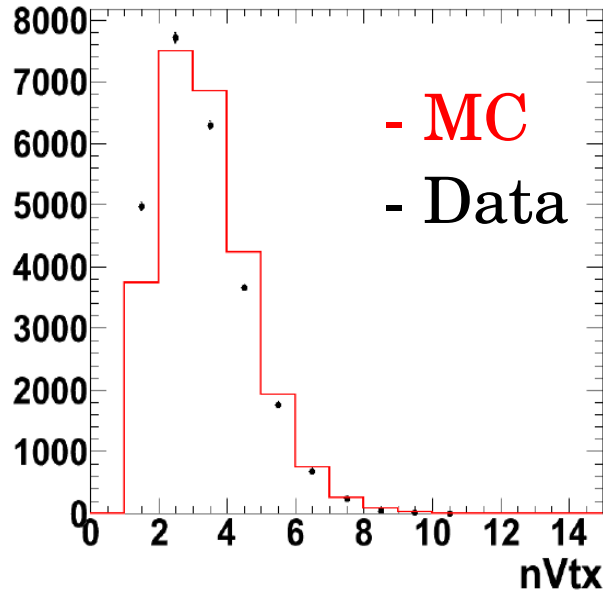
	Passing	Failing
Barrel		
0 - 0.5	0.34%	0.98%
0.5 - 1.0	0.45%	1.25%
1.0 - 1.4442	0.81%	1.83%
TOT	0.52%	1.24%
Endcap		
1.566 - 1.8	1.87%	2.82%
1.8 - 2.1	2.00%	2.72%
2.1 - 2.5	2.67%	3.85%
TOT	2.21%	3.07%

- No factorization is involved here, it has to be checked if factorization could help in reducing uncertainty.

E_T	MC	DATA	R (DATA/MC)
Barrel			
20 - 35	$86.97 \pm 0.16 \%$	$86.22 \pm 0.48 \pm 1.59 \%$	0.991 ± 0.019
35 - 45	$92.21 \pm 0.11 \%$	$90.53 \pm 0.34 \pm 0.59 \%$	0.981 ± 0.008
45 - inf	$93.61 \pm 0.13 \%$	$91.08 \pm 0.44 \pm 0.17 \%$	0.973 ± 0.005
Endcap			
20 - 35	$88.54 \pm 0.22 \%$	$88.98 \pm 0.60 \pm 2.17 \%$	1.005 ± 0.025
35 - 45	$93.20 \pm 0.16 \%$	$93.04 \pm 0.48 \pm 0.99 \%$	0.998 ± 0.012
45 - inf	$94.94 \pm 0.20 \%$	$94.26 \pm 0.66 \pm 0.21 \%$	0.993 ± 0.007

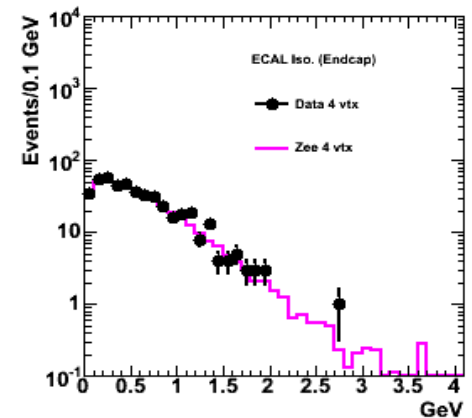
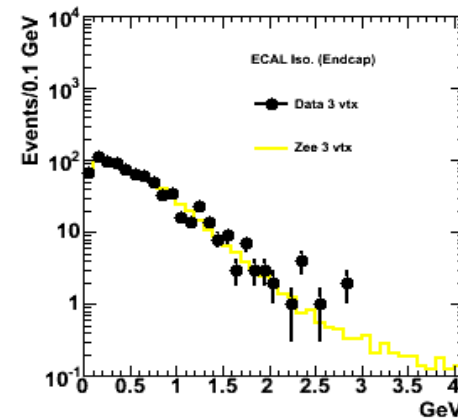
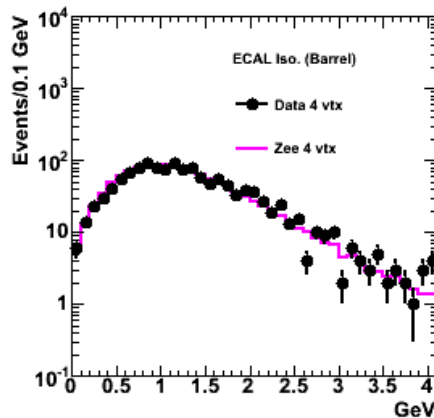
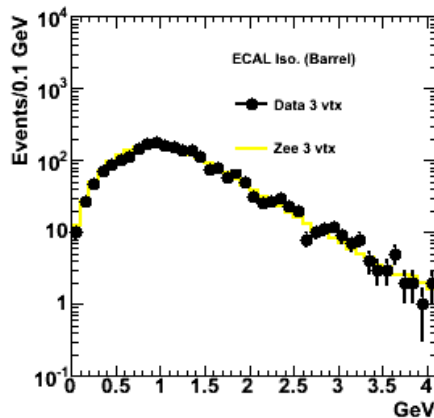
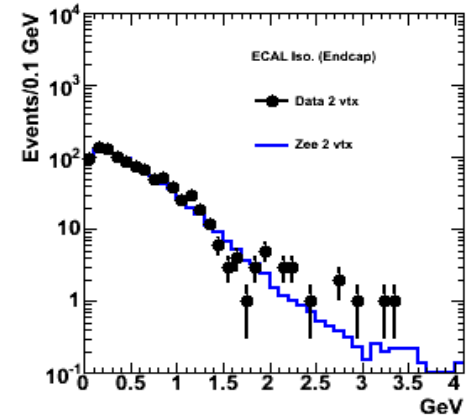
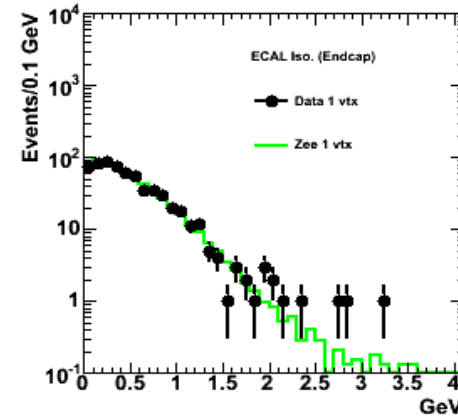
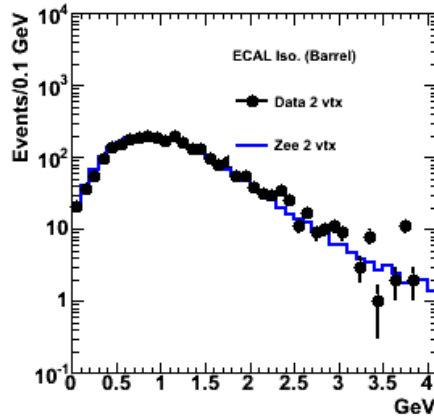
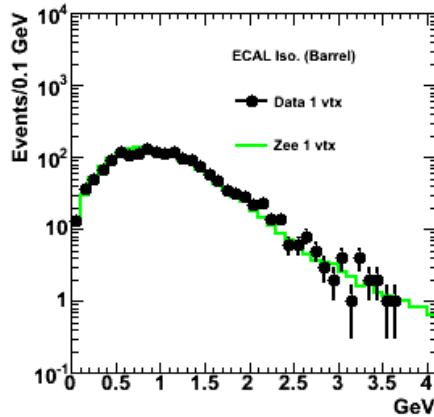
Results available also as a function of eta, fBrem and R9.

- Recently MC samples with pileup have been simulated.



- We have compared signal MC with pileup to estimate the effect on the selection efficiency:
 - Exotica Selection: $MC/MC_{PU} = 1.01$ (BARREL), 1.001 (ENDCAP)
 - Hgg Selection: $MC/MC_{PU} = 1.05$ (BARREL), 1.01 (ENDCAP)

Pileup Data/MC Comparison



BARREL

ENDCAP

- We have measured various photon selection efficiencies using Z Tag and Probe method using $\sim 35 \text{ pb}^{-1}$ of data.
- We have tested three different techniques: counting, fit and opposite sign-same sign:
 - the same methods will be used to measure electron efficiencies as well.
- The three results are in good agreement:

	COUNT	FIT	OS/SS
BARREL	0.981 ± 0.008	0.967 ± 0.011	0.982 ± 0.011
ENDCAP	0.991 ± 0.007	0.983 ± 0.016	0.994 ± 0.013

- We have also studied the selection efficiencies as a function of the number of reco vertices to check pileup effect.